

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination RAMDANI ET AL.	
		Examiner B. William Baumeister	Art Unit 2815	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,478,653	12-1995	Guenzer, Charles S.	428/446
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	52-89070	07-1977	Japan	Serizawa	H01L 21/20
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kaushik et al., "Device Characteristics of Crystalline Epitaxial Oxides on Silicon," Device Research Conference, 2000, Conference Digest 58 th DRC, pp. 17-20, June 19-21, 2000.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.